

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s):

Michael Zhuoying Su

Title:

INTERCONNECT SPEED SENSING CIRCUITRY

Application No.: 10/700,902

Filed:

November 4, 2003

Examiner:

Not Yet Assigned

Group Art Unit: 2811

Atty. Docket No.: 1001-0263

February 11, 2004

COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, § 1.97 and § 1.98, the undersigned brings the patents, publications, applications or other information identified in the attached:

Form(s) PTO-1449

Other: n/a

to the Examiner's attention in the above-identified application. Citation of such information shall not be construed as:

- an admission that the information necessarily is, or corresponds to, prior art with 1. respect to the instant invention;
- a representation that a search has been made, other than as described below; or 2.
- 3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

For each item of information listed that is not in the English language, the undersigned has provided a concise explanation of the relevance through (i) an English language abstract, (ii) an English language equivalent application, or (iii) if cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action that indicates the degree of relevance found by the foreign office.

FEE AUTHORIZATION

This Information Disclosure Statement is filed within three months of the filing
date of a national application other than a continued prosecution application under
§ 1.53(d) or within three months of entry of the national stage as set forth in
§ 1.491 in an international application. Therefore, no fee is required.

The undersigned believes that this Information Disclosure Statement is being filed before the mailing date of a first Office action on the merits or before the mailing date of a first Office action after the filing of a request for continued examination under § 1.114. Therefore, no fee is believed required.

If however, this Information Disclosure Statement is filed after the period specified in § 1.97(b), the undersigned hereby authorizes the Commissioner to charge the fee set forth in § 1.17(p) to Deposit Account No. 50-0631.

	CERTIFICATE	OF MAILIN	G OR TRA	NSMISSION
--	-------------	-----------	----------	-----------

I hereby certify that, on the date shown below, this correspondence is being

- deposited with the US Postal Service with sufficient postage as first class mail, in an envelope addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.
- facsimile transmitted to the US Patent and Trademark Office.

Micole Teitler Cave Date

EXPRESS MAIL LABEL:

Respectfully submitted,

Nicole Teitler Cave, Reg. No. 54,021

Attorney for Applicant(s)

(512) 338-6315

(512) 338-6301 (fax)

	nt of Cor	mmerce, Patent and Trademar		Attorney Docket No.:	1001-0263	-		
•			Application No.:	10/700,902				
	DRMA"	ΓΙΟΝ DISCLOSURE STAT	Applicant(s):	Michael Zhuoying Su				
/6	1	(Use several sheets if r	Filing Date:	November 4, 2003				
FEB 1	7 2004	2		Group Art Unit:	Group Art Unit: 2811			
		7			Date Submitted:	February 11, 2	2004	
THE TOA			U.S. Patent Docu	iments				
*Examiner Initial		Document Number	Date		Name			
	AA	6,345,209	02-05-2002	Yu				
	AB	6,207,553	03-27-2001	Buynosk	i et al.			
	AC							
	AD							
	AE							
	AF							
	AG		,					
	AH							
	ΑI						•	
	AJ							
	AK							
			Foreign Patent Do	cuments		T _		
1		Downward Date Control			Translation			
	AL	Document	Date		Country	Yes	No	
	AM			-				
	AN							
	AP							
<u> </u>		OTHER ART	(Including Author, Title,	Date, Pertin	ent Pages, Etc.)		·	
	AR	NEIL H. E. WESTE and K	AMRAN ESHRAGHIAN	, Principles of	f CMOS VLSI Design, A S	Systems Perspec	tive,	
	AS	Second Edition, Addison-Wesley Publishing Co., Copyright 1993 by AT&T, pp. 191-198. TOM PYE and PETER ROSE, Low-Dielectric-Constant Materials for Back-End-of-Line Applications, Semiconductor Fabtech, 8 th Edition, pp. 203-207.						
	АТ							
Examiner			Date Considered					